

Search Notes



Application/Control No.

09/881,001

Examiner

Tan Dean D. Nguyen

Applicant(s)/Patent under Reexamination

LOF ET AL.

Art Unit

3629

SEARCHED

Class	Subclass	Date	Examiner
705	1	7/06	DN
	412		
	413		
364	148.01		
	149		
307	29		
	45		
	47		

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)

	DATE	EXMR
I US	7/06	DN
Patent PG Pub		
II FOREIGN		
1. EPO		
2. JPO		
3. Derwent		